

Issue Classification			Application/Control No.	Applicant(s)/Patent under Reexamination	
			10/791,135	CHEN ET AL.	
			Examiner	Art Unit	
			Jinhee J. Lee	2831	

ISSUE CLASSIFICATION					
ORIGINAL			CROSS REFERENCE(S)		
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)		
174	99r	174	100	72a	
INTERNATIONAL CLASSIFICATION					
a	6	3	b	21/06	
			/		
			/		
			/		
			/		
Jinhee Lee (Assistant Examiner) (Date) <i>Dorion Evans</i> 4/6/05 (Legal Instruments Examiner) (Date)			Dean A. Reichard DEAN A. REICHARD SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800 (Primary Examiner) (Date) <i>4/4/05</i>		
			Total Claims Allowed: 7		
			O.G. Print Claim(s) 1	O.G. Print Fig. 3a, 3b, 4f	

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R. 1.47	
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